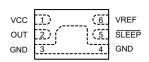
Micro Power 3V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

Package EH, 6-pin MLP/DFN





ABSOLUTE MAXIMUM RATINGS*

Supply Voltage, V _{CC} 8 V
Reverse-Supply Voltage, V _{RCC} 0.1 V
Ratiometric Supply Reference Voltage, V _{REF} 7 V
Reverse-Ratiometric Supply
Reference Voltage, V _{RREF} 0.1 V
Logic Supply Voltage, V _{SLEEP}
$(V_{CC} > 2.5 \text{ V})$ 32 V
Reverse-Logic Supply Voltage, V _{RSLEEP} 0.1 V
Output Voltage, V_{OUT} V_{CC} + 0.1 V
Reverse-Output Voltage, V _{ROUT} 0.1 V
Temperatures
Operating Ambient, T _A , Range S – 20°C to 85°C
Junction, T _{J(MAX)} 165°C
Storage, T _S 65°C to 170°C
*All ratings with reference to ground.

These linear Hall effect sensor integrated circuits (ICs) provide a voltage output that is directly proportional to an applied magnetic field. Before amplification, the sensitivity of typical Hall effect ICs (measured in mV/G) is directly proportional to the current flowing through the Hall effect transducer element inside the ICs. In many applications, it is difficult to achieve sufficient sensitivity levels with a Hall effect sensor IC without consuming more than 3 mA of current. The A1391 and A1392 minimize current consumption to less than 25 μ A through the addition of a user-selectable sleep mode. This makes these devices perfect for battery-operated applications such as: cellular phones, digital cameras, and portable tools. End users can control the current consumption of the A1391 and A1392 by applying a logic level signal to the $\overline{\text{SLEEP}}$ pin. The outputs of the devices are not valid (high-impedance mode) during sleep mode. The high-impedance output feature allows the connection of multiple A1391 and A1392 Hall effect devices to a single A-to-D converter input.

The quiescent output voltage of these devices is 50 % nominal of the ratiometric supply reference voltage applied to the VREF pin of the device. The output voltage of the device is not ratiometric with respect to the SUPPLY pin.

Despite the low power consumption of the circuitry in the A1391 and A1392, the features required to produce a highly-accurate linear Hall effect IC have not been compromised. Each BiCMOS monolithic circuit integrates a Hall element, improved temperature-compensating circuitry to reduce the intrinsic sensitivity drift of the Hall element, a small-signal high-gain amplifier, and proprietary dynamic offset cancellation circuits. End of line, post-packaging, factory programming allows precise control of device sensitivity and offset.

This device is available in a small 2.0×3.0 mm, 0.75 mm nominal height micro leaded package (MLP). It is Pb (lead) free, with 100 % matter tin leadframe plating.

Features and Benefits

- · High-impedance output during sleep mode
- Compatible with 2.5 to 3.5 V power supplies
- 10 mW power consumption in the active mode
- · Miniature MLP package
- Ratiometric output scales with the ratiometric supply reference voltage (VREF pin)
- · Temperature-stable quiescent output voltage and sensitivity
- Wide ambient temperature range: -20°C to 85°C
- · ESD protection greater than 3 kV
- · Solid-state reliability
- · Preset sensitivity and offset at final test



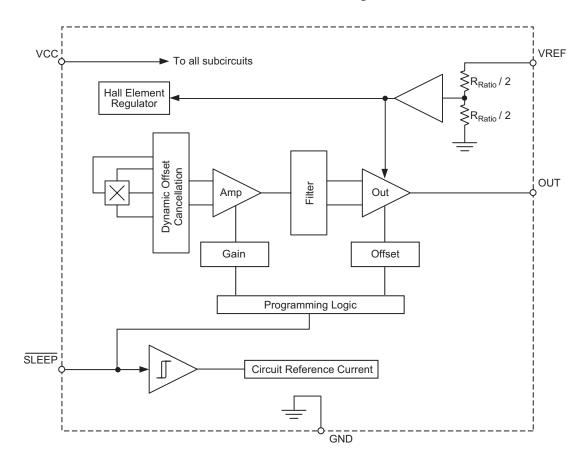
Use the following complete part numbers when ordering:

Part Number	Sensitivity (mV/G, Typ.)	Packing*
A1391SEHLT-T	1.25	7-in. reel, 3000 pieces/reel
A1392SEHLT-T	2.50	7-in. reel, 3000 pieces/reel

^{*}Contact Allegro for additional packing options.



Functional Block Diagram



Terminal List Table

Pin	Name	Function
1	VCC	Supply
2	OUT	Output
3	GND	Ground
4	GND	Ground
5	SLEEP	Toggle sleep mode
6	VREF	Supply for ratiometric reference

Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

Device Characteristics Tables

ELECTRICAL CHARACTERISTICS valid through full operating ambient temperature range, unless otherwise noted

Characteristic	Symbol	Test Conditions	Min.	Typ. ¹	Max.	Units
Supply Voltage	V _{CC}		2.5	_	3.5	V
Nominal Supply Voltage	V _{CCN}		_	3.0	_	V
Supply Zener Clamp Voltage	V _{CCZ}	I _{CC} = 7 mA, T _A = 25°C	6	8.3	_	V
Ratiometric Reference Voltage ²	V_{REF}		2.5	_	V _{CC}	V
Ratiometric Reference Zener Clamp Voltage	V_{REFZ}	I _{VREF} = 3 mA, T _A = 25°C	6	8.3	_	V
SLEEP Input Voltage			-0.1	_	V _{CC} + 0.5	V
SLEEP Input Threshold	V _{INH}	For active mode	_	0.45 × V _{CC}	_	V
SLEEF Input Tilleshold	V _{INL}	For sleep mode	_	0.20 × V _{CC}	_	V
Ratiometric Reference Input Resistance	D	$V_{SLEEP} > V_{INH}$, $V_{CC} = V_{CCN}$, $T_A = 25$ °C	250	_	_	kΩ
	R_REF	$V_{\text{SLEEP}} < V_{\text{INL}}, V_{\text{CC}} = V_{\text{CCN}},$ $T_{\text{A}} = 25^{\circ}\text{C}$	_	5	_	МΩ
Chopper Stabilization Chopping Frequency	f _C	$V_{CC} = V_{CCN}, T_A = 25^{\circ}C$	_	200	_	kHz
SLEEP Input Current	I _{SLEEP}	$V_{SLEEP} = 3 V, V_{CC} = V_{CCN}$	_	1	_	μΑ
Supply Current ³	1	$V_{\text{SLEEP}} < V_{\text{INL,}} V_{\text{CC}} = V_{\text{CCN,}}$ $T_{\text{A}} = 25^{\circ}\text{C}$	_	0.025	_	mA
	I _{CC}	$V_{SLEEP} > V_{INH}$, $V_{CC} = V_{CCN}$, $T_A = 25$ °C	_	3.2	_	mA
Quiescent Output Power Supply Rejection ⁴	PSR _{VOQ}	f _{AC} < 1 kHz	_	- 60	_	dB

 $^{^1}$ Typical data are for initial design estimations only, and assume optimum manufacturing and application conditions, such as T_A = 25°C. Performance may vary for individual units, within the specified maximum and minimum limits.



² Voltage applied to the VREF pin. Note that the V_{REF} voltage must be less than or equal to V_{cc}. Degradation in device accuracy will occur with applied voltages of less than 2.5 V.

 $^{^3}$ If the VREF pin is tied to the VCC pin, the supply current would be I $_{\rm CC}$ + V $_{\rm REF}$ / R $_{\rm REF}$

 $^{^4\,\}mathrm{f_{AC}}$ is any ac component frequency that exists on the supply line.

Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

OUTPUT CHARACTERISTICS valid through full operating ambient temperature range, unless otherwise noted

Characteristic	Symbol		Test Conditions		Typ. ¹	Max.	Units
Output Voltage Saturation	V _{OUTH}	B = X ,	$B = X$, $V_{CC} = V_{CCN}$, $V_{REF} \le V_{CC}$		V _{REF} – 0.1	_	V
Limits ²	V _{OUTL}	B = - X	$V_{CC} = V_{CCN}, V_{REF} \le V_{CC}$	_	0.1	_	V
Maximum Voltage Applied to Output	V _{OUTMAX}	V _{SLEEP}	< V _{INL}	_	-	V _{CC} + 0.1	V
Sensitivity ³	Sens		$T_A = 25$ °C, $V_{CC} = V_{REF} = V_{CCN}$	1.18	1.25	1.31	mV/G
Sensitivity	Selis	A1392	$T_A = 25$ °C, $V_{CC} = V_{REF} = V_{CCN}$	2.35	2.50	2.65	mV/G
Quiescent Output	V _{OUTQ}	T _A = 25	°C, B = 0 G	-	0.500 × V _{REF}	(0.500 × V _{REF}) ± 0.030	V
Output Resistance ⁴	R _{OUT}	$f_{out} = 1$	kHz, V _{SLEEP} > V _{INH} , active mode	_	20	_	Ω
		$f_{out} = 1$	kHz, V _{SLEEP} < V _{INL} , sleep mode	_	4M	_	Ω
Output Load Resistance	R _L	Output	Output to ground		_	_	kΩ
Output Load Capacitance	C _L	Output	Output to ground		_	10	nF
Output Bandwidth	BW	-3 dB p	-3 dB point, $V_{OUT} = 1 V_{pp}$ sinusoidal, $V_{CC} = V_{CCN}$		10	-	kHz
Noise ^{5,6}	V _n	1391	$C_{bypass} = 0.1 \mu F,$ $BW_{externalLPF} = 2 \text{ kHz}$	_	6	12	mV _{pp}
			$C_{bypass} = 0.1 \mu F$, no load	_	_	20	mV_{pp}
		1392	$C_{bypass} = 0.1 \mu F$, no load	_	_	40	mV_{pp}

 $^{^{1}}$ Typical data are for initial design estimations only, and assume optimum manufacturing and application conditions, such as T_A = 25°C. Performance may vary for individual units, within the specified maximum and minimum limits.



²This test requires positive and negative magnetic fields sufficient to swing the output driver between fully OFF and saturated (ON), respectively. The value of vector **X** is NOT intended to indicate a range of linear operation.

 $^{^{3}}$ For V_{REF} values other than V_{REF} = V_{CCN} , the sensitivity can be derived from the following equation: 0.416 × V_{REF}

⁴f OUT is the output signal frequency_

⁵Noise specification includes digital and analog noise.

⁵Values for BW_{externalLPF} do not include any noise resulting from noise on the externally-supplied VREF voltage.

Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

OUTPUT TIMING CHARACTERISTICS¹ T_A = 25°C

Characteristic	Symbol	Test Conditions	Min.	Typ. ²	Max.	Units
Power-On Time ³	t _{PON}		-	40	60	μs
Power-Off Time ⁴	t _{POFF}		-	1	_	μs

¹See figure 1 for explicit timing delays.

MAGNETIC CHARACTERISTICS $T_A = 25$ °C

Characteristic	Symbol	Test Conditions	Min.	Тур.*	Max.	Units
Ratiometry	$\Delta V_{OUTQ(\Delta V)}$		_	100	_	%
Ratiometry	$\Delta Sens_{(\Delta V)}$		_	100	_	%
Positive Linearity	Lin+		_	100	_	%
Negative Linearity	Lin-		_	100	_	%
Symmetry	Sym			100	_	%

^{*}Typical data are for initial design estimations only, and assume optimum manufacturing and application conditions, such as $T_A = 25$ °C. Performance may vary for individual units, within the specified maximum and minimum limits.



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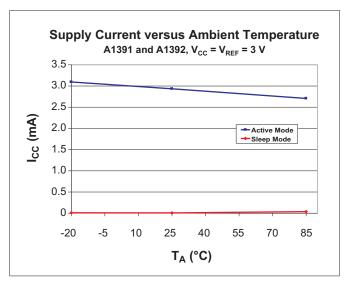
²Typical data are for initial design estimations only, and assume optimum manufacturing and application conditions, such as T_A = 25°C. Performance may vary for individual units, within the specified maximum and minimum limits.

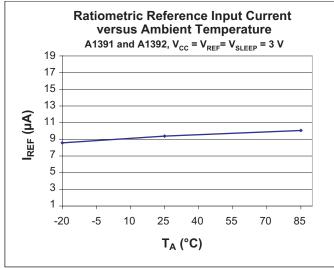
³Power-On Time is the elapsed time after the voltage on the SLEEP pin exceeds the active mode threshold voltage, V_{INH}, until the time the device output reaches 90% of its value. When the device output is loaded with the maximum capacitance of 10 nF, the Power-On Time range is guaranteed for input SLEEP pin frequencies less than 10 Hz.

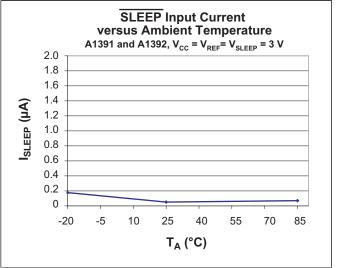
⁴Power-Off Time is the duration of time between when the signal on the SLEEP pin switches from HIGH to LOW and when I_{CC} drops to under 100 µA. During this time period, the output goes into the HIGH impedance state.

Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

Electrical Characteristic Data

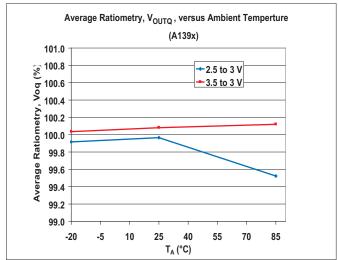


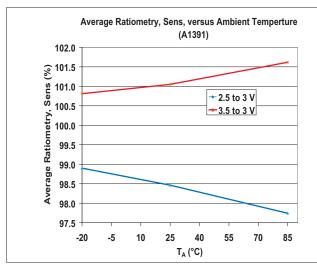


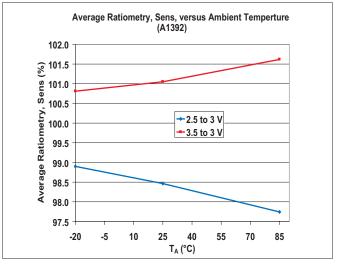


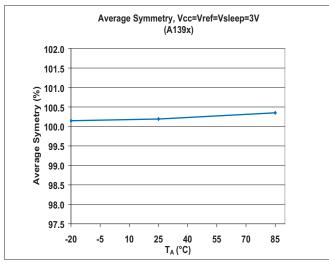
Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

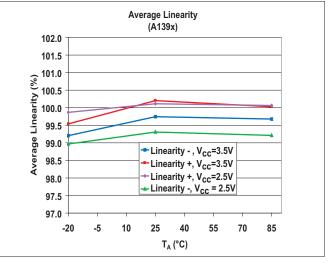
Magnetic Characteristic Data











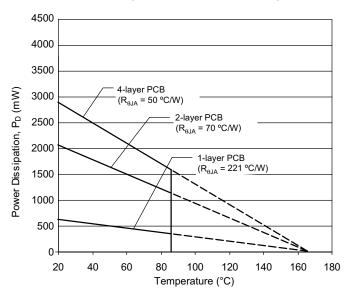
Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

THERMAL CHARACTERISTICS may require derating at maximum conditions, see application information

Characteristic	Symbol	Test Conditions*	Min.	Units
Package Thermal Resistance		1-layer PCB with copper limited to solder pads	221	°C/W
	$R_{ heta JA}$	2-layer PCB with 0.6 in. ² of copper area each side, connected by thermal vias	70	°C/W
		4-layer PCB based on JEDEC standard	50	°C/W

^{*}For additional information, see Allegro Web site.

Power Dissipation versus Ambient Temperature





Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

Characteristics Definitions

Ratiometric. The A1391 and A1392 devices feature ratiometric output. The quiescent voltage output and sensitivity are proportional to the ratiometric supply reference voltage. The percent ratiometric change in the quiescent voltage output is defined as:

$$\Delta V_{\text{OUTQ(\Delta V)}} = \frac{\Delta V_{\text{OUTQ(V_{REF})}} \dot{-} \Delta V_{\text{OUTQ(3V)}}}{V_{\text{REF}} \dot{-} 3 \text{ V}} \times 100 \% \tag{1}$$

and the percent ratiometric change in sensitivity is defined as:

$$\Delta Sens_{(\Delta V)} = \frac{\Delta Sens_{(V_{REF})^{\div}} \Delta Sens_{(3V)}}{V_{REF} \div 3 V} \times 100\%$$
 (2)

Linearity and Symmetry. The on-chip output stage is designed to provide a linear output with maximum supply voltage of V_{CCN}. Although application of very high magnetic fields will not damage these devices, it will force the output into a non-linear region. Linearity in percent is measured and defined as

$$Lin+ = \frac{V_{OUT(+B)} - V_{OUTQ}}{2(V_{OUT(+B/2)} - V_{OUTQ})} \times 100\%$$
 (3)

$$Lin- = \frac{V_{OUT(-B)} - V_{OUTQ}}{2(V_{OUT(-B/2)} - V_{OUTQ})} \times 100\%$$
 (4)

and output symmetry as

$$Sym = \frac{V_{OUT(+B)} - V_{OUTQ}}{V_{OUTQ} - V_{OUT(-B)}} \times 100\%$$
(5)



Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

Device Low-Power Functionality

A1391 and A1392 are low-power Hall effect sensor ICs that are perfect for power sensitive customer applications. The current consumption of these devices is typically 3.2 mA, while the device is in the active mode, and less than 25 uA when the device is in the sleep mode. Toggling the logic level signal connected to the SLEEP pin drives the device into either the active mode or the sleep mode. A logic low sleep signal drives the device into the sleep mode, while a logic high sleep signal drives the device into the active mode.

In the case in which the VREF pin is powered before the VCC pin, the device will not operate within the specified limits until the supply voltage is equal to the reference voltage. When the device is switched from the sleep mode to the active mode, a time defined by t_{PON} must elapse before the output of the device is

valid. The device output transitions into the high impedance state approximately t_{POFF} seconds after a logic low signal is applied to the $\overline{\text{SLEEP}}$ pin (see figure 1).

If possible, it is recommended to power-up the device in the sleep mode. However, if the application requires that the device be powered on in the active mode, then a 10 k Ω resistor in series with the SLEEP pin is recommended. This resistor will limit the current that flows into the SLEEP pin if certain semiconductor junctions become forward biased before the ramp up of the voltage on the VCC pin. Note that this current limiting resistor is not required if the user connects the SLEEP pin directly to the VCC pin. The same precautions are advised if the device supply is powered-off while power is still applied to the SLEEP pin.

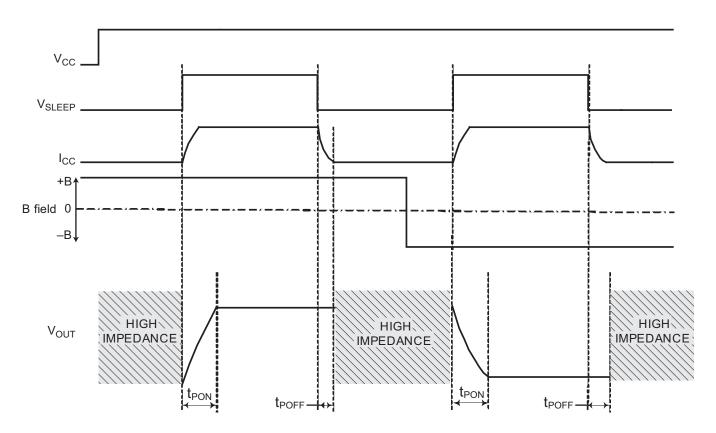


Figure 1. A1391/A1392 Timing Diagram



Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

Device Supply Ratiometry Application Circuit

Figures 2 and 3 present applications where the VCC pin is connected together with the VREF pin of the A1391/A1392. Both of these pins are connected to the battery, Vbat2. In this case, the device output will be ratiometric with respect to the battery voltage.

The only difference between these two applications is that the SLEEP pin in figure 2 is connected to the Vbat2 potential, so the device is always in the active mode. In figure 3, the SLEEP pin is toggled by the microprocessor; therefore, the device is selectively and periodically toggled between active mode and sleep mode.

In both figures, the device output is connected to the input of an A-to-D converter. In this configuration, the converter reference voltage is Vbat1.

It is strongly recommended that an external bypass capacitor be connected, in close proximity to the A1391/-92 device, between the VCC and GND pins of the device to reduce both external noise and noise generated by the chopper-stabilization circuits inside of the A1391/A1392.

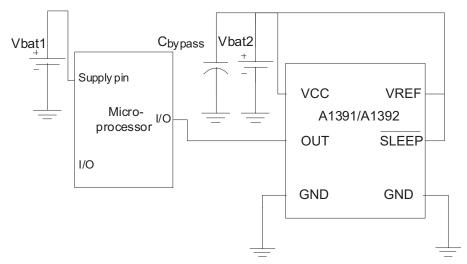


Figure 2. Application circuit showing sleep mode disabled and output ratiometirc to the A1391/A1392 supply.

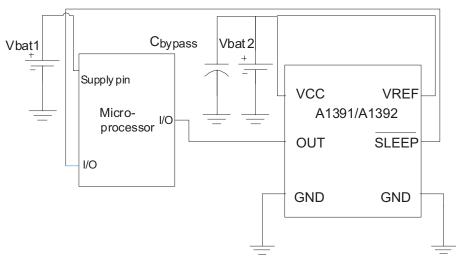


Figure 3. Application circuit showing microprocessor-controlled sleep mode and output ratiometirc to the A1391/A1392 supply.



Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

Application Circuit with User-Configurable Ratiometry

In figures 4 and 5, the microprocessor supply voltage determines the ratiometric performance of the A1391/A1392 output signal. As in the circuits shown in figures 2 and 3, the device is powered by the Vbat2 supply, but in this case, ratiometry is determined by the microprocessor supply, Vbat1.

The SLEEP pin is triggered by the output logic signal from the microprocessor in figure 5, while in figure 4, the SLEEP pin is connected to the device power supply pin. Therefore, the device as configured in figure 4 is constantly in active mode, while the device as confingred in figure 5 can be periodically toggled

between the active and sleep modes.

The capacitor C_{filter} is optional, and can be used to prevent possible noise transients from the microprocessor supply reaching the device reference pin, VREF.

It is strongly recommended that an external bypass capacitor be connected, in close proximity to the A1391/A1392 device, between the VCC and GND pins of the device to reduce both external noise and noise generated by the chopper-stabilization circuits inside of the A1391/A1392.

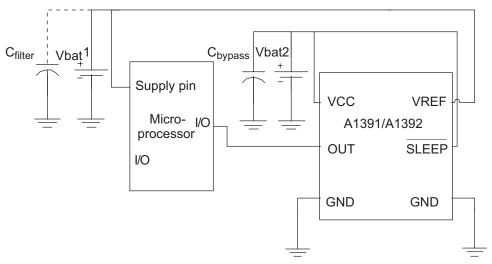


Figure 4. Application circuit showing ratiometry of V_{REF} . Sleep mode is disabled and the VREF pin is tied to the microprocessor supply.

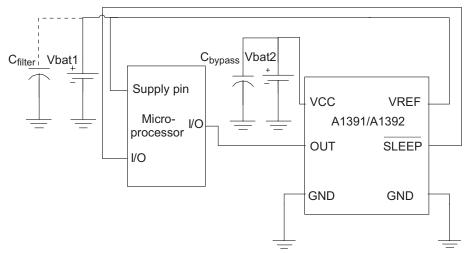
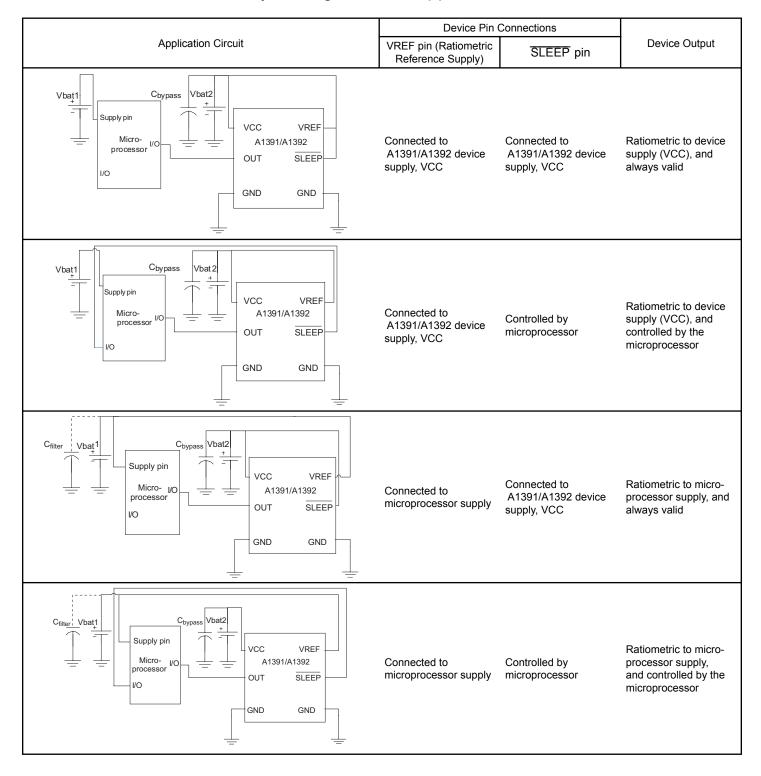


Figure 5. Application circuit showing device reference pin, VREF, tied to microprocessor supply. The device sleep mode also is controlled by the microprocessor.



Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

Summary of Single-Device Application Circuits





Application Circuit with Multiple Hall Devices and a Single A-to-D Converter

Multiple A1391/A1392 devices can be connected to a single microprocessor or A-to-D converter input. In this case, a single device is periodically triggered and put into active mode by the microprocessor. While one A1391/A1392 device is in active mode, all of the other A1391/A1392 devices must remain in sleep mode. While these devices are in sleep mode, their outputs are in a high-impedance state. In this circuit configuration, the microprocessor reads the output of

one device at a time, according to microprocessor input to the SLEEP pins.

When multiple device outputs are connected to the same microprocessor input, pulse timing from the microprocessor (for example, lines A1 through A4 in figure 6) must be configured to prevent more than one device from being in the awake mode at any given time of the application. A device output structure can be damaged when its output voltage is forced above the device supply voltage by more than 0.1 V.

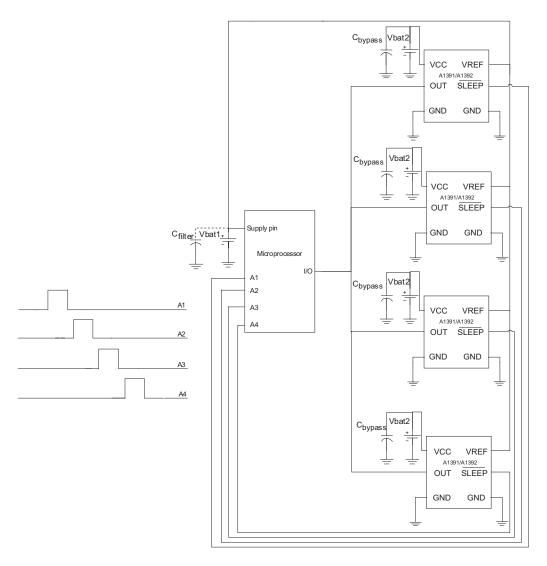
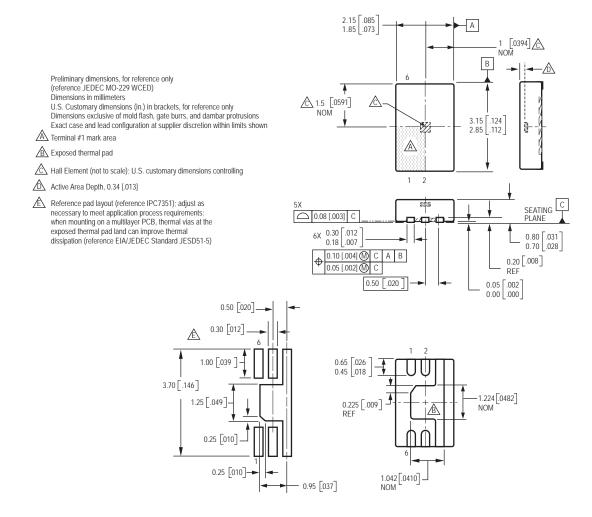


Figure 6. Application circuit showing multiple A1391/A1392 devices, controlled by a single microprocessor.



Micro Power 3 V Linear Hall Effect Sensor with Tri-State Output and User-Selectable Sleep Mode

Package EH, 6-pin MLP



The products described herein are manufactured under one or more of the following U.S. patents: 5,045,920; 5,264,783; 5,442,283; 5,389,889; 5,581,179; 5,517,112; 5,619,137; 5,621,319; 5,650,719; 5,686,894; 5,694,038; 5,729,130; 5,917,320; and other patents pending.

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